PRODUCT/PROCESS CHANGE NOTIFICATION Generic Copy

03-OCT-2000

SUBJECT: ON Semiconductor Update Notification 10277

TITLE: ADDENDUM TO PCN10187-PSI QUAL FOR TO-264, TO-247 AND TO-218

EFFECTIVE DATE: 02-Dec-2000

AFFECTED CHANGE CATEGORY(S):

ON SEMICONDUCTOR ASSEMBLY SITE

AFFECTED PRODUCT DIVISION(S):

MOS POWER PRODUCTS DIV
BIPOLAR DISCRETES PRODUCTS DIV

ADDITIONAL RELIABILITY DATA: None

SAMPLES: No

(SEE ADDITIONAL INFO SECTION)

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION: Contact Sales Office (LINDA HAYES, RV8090@onsemi.com)

DISCLAIMER:

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact your local ON Semiconductor sales office.

DESCRIPTION AND PURPOSE:

Reason for addendum: Provide updates to PCN 10187, originally released June 13, 2000. The reliability results of specific devices shown on page 4 of the original PCN are updated, as well as the addition of 30 more devices that are included in the transfer. Note that TO-218 2-leaded Ultrafast Rectifiers were part of the scope of the original PCN, but now are excluded due to lack of equipment capacity at PSi (Pacific Semiconductors Industries).

ON Semiconductor is pleased to announce that it has qualified PSi as a qualified manufacturer and tester of the large size plastic packages known as the TO-264, the TO-247, and the TO-218 (a.k.a. SOT93). We currently manufacture the TO-264 in Team Pacific and the TO-247 and TO-218 at ST Microelectronics.



PSi has been a manufacturer to ON Semiconductor, formerly as a division of Motorola, for more that 20 years, manufacturing the TO-220, D Pak and DD Pak. PSi is a member of the Semiconductor Assembly Council and received the Philippines 1999 Quality Award for Outstanding Quality. The mentioned packages will be manufactured using the same high quality materials on equipment capable of meeting the high quality standards of ON Semiconductor. Devices from PSi can be identified with the Location Identifier CQ preceding the date code. Qualification of the various technologies and packages is in process and in the following cases completed. Qualification includes the AEC Q101 requirements on all MOSFET devices. ON Semiconductor continues to make substantial investments in both new technologies and improved manufacturing capabilities to provide the highest quality and most reliable products in the industry. We believe that these actions will provide the capability to provide a continuous supply of quality devices to you through the future.

Devices included on PCN10187, which expired on September 22, 2000:

MTY100N10E

MTY55N20E

MTY30N50E

MTY20N50E

MTY25N60E

MJL21193

MJL21194

MJL21195

MJL21196

MJL1302A

MJL3281A

MJL16218

MTW32N25E

MTW24N40E

MTW20N50E

MTW7N80E

MTW6N100E

MTW10N100E

MTW16N40E

MTW14N50E

MTW8N60E

STW1019

MTW20N20E

MTW32N20E

MJW21191 MJW21192

TE02549

MBR4045PT

MBR6045PT MBR 3045PT

SBR5571-002

MUR3020PT

MUR3040PT

MUR3060PT MUR3040PT

MUR3080

MUR6040

TIP2955

TTP3055

TIP33A

TIP33C

TTP36A

TIP36C

BD249C TIP35A

TIP35C



MJE4343 MJE4353 BDV65B TIP140 TIP141 TIP142 MJH10012 MJH6284 MJH6287 MJH11018 MJH11020 MJH11022 MJH11017 MJH11019

Additional Devices for this update:

MUR3020WT

MJH11021 BU323AP TE02390

MUR3060WT

MBR4015LWT

MBR4045WT

MBR6045WT

MBR7030WT

MTW45N10E

MTW35N15E

MTW8N50E

MJL21196

MBR3045WT

MUR16006A

BDV64B

TIP145

TIP146

TIP147

MTW35N15E

BUV48

MJW18020

BU323Z

SJE2448

MJW16010A

MJW16010

MJW16206

MJW16018

MJW16212

BUS48AP BUV48A

TE02486

TE02454

TE02570

QUALIFICATION PLAN:

CONDITIONS **EXCEPTIONS**

H3TRB Ta=85 deg. C, RH= 85%, 1000 hrs.

ESD HBM

ESD HBM HTRB Ta=150 deg.C, 1000 hrs.

Ta=25 deg.C, delta Tj =>100 deg.C,
5 minutes on/off, 5000 cycles
Temp Cycle Air to Air, -65 to 150 deg.C
1000 cycles

Autoclave Ta=121 deg. C, RH= 100%, PSIg= 15, 96 hrs.
HTGB Ta=150 deg.C, 1000 hrs.

for MOSFET only.

QUALIFICATION VEHICLE JUSTIFICATION:

FAMILY	QUAL DEVICE	REASON CHOSEN
TO-264 Bipolar Power	MJL21193	Largest die size, complex PNP device
TO-247 Bipolar Power	MJW21191	Large die size, High Voltage
TO-218 Bipolar Power	MJH16006A	Large die size, High Voltage
TO-264 MOSFET	MTY25N60E	Large die size
TO-247 MOSFET	MTW10N100E	Highest voltage
TO-247	MTW35N15E	Standard equivalent
MOSFET TO-247 Rectifier	MBR7030WT	for Automotive Largest die, Schottky

RELIABILITY DATA SUMMARY:

DEVICE:MJL21193

TEST DESCRIPTION	Lot 1	Lot 2	Lot 3	Control
1000 hrs. ESD HTRB	0/80 pass	0/80 pass	0/80 pass	0/80 pass
1000 hrs.	0/80	0/80	0/80	0/80
5000 cycles Temp Cycle	0/80	0/80	0/80	0/80
1000 cycles	0/80	0/80	0/80	0/80
Autoclave 96 hrs.	0/80	0/80	0/80	0/80

^{*}MOSFET devices were qualifed per AEC-Q-101 guidelines.



DEVICE:MTW35N15E				
TEST DESCRIPTION H3TRB	Lot 1	Lot 2	Lot 3	Control
1000 hrs.	0/80	0/80	0/80	0/80
ESD	pass	pass	pass	pass
HTRB 1000 hrs.	0/80	0/80	0/80	0/80
IOL 5000 cycles	0/80	0/80	0/80	0/80
Temp Cycle				
1000 cycles Autoclave	0/80	0/80	0/80	0/80
96 hrs.	0/80	0/80	0/80	0/80
HTGB 1000 hrs	0/80	0/80	0/80	0/80
1000 1115	0,00	0,00	0,00	0,00
DEVICE:MTW10N100E	T a.b. 1	T - 1 0	T - 1 2	Combonal
TEST DESCRIPTION H3TRB	Lot 1	Lot 2	Lot 3	Control
1000 hrs.	0/80	0/80	0/80	0/80
ESD HTRB	pass	pass	pass	pass
1000 hrs.	0/80	0/80	0/80	0/80
IOL	0 / 0 0	0 / 0 0	0.700	0 / 0 0
5000 cycles Temp Cycle	0/80	0/80	0/80	0/80
1000 cycles	0/80	0/80	0/80	0/80
Autoclave 96 hrs.	0/80	0/80	0/80	0/80
HTGB	0/80	0/80	0/80	0780
1000 hrs	0/80	0/80	0/80	0/80
MTY25N60E				
TEST DESCRIPTION	Lot 1	Lot 2	Lot 3	Control
TEST DESCRIPTION H3TRB				
TEST DESCRIPTION	Lot 1 0/80 pass	Lot 2 0/80 pass	Lot 3 0/80 pass	Control 0/80 pass
TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB	0/80 pass	0/80 pass	0/80 pass	0/80 pass
TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs.	0/80	0/80	0/80	0/80
TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs. IOL 5000 cycles	0/80 pass	0/80 pass	0/80 pass	0/80 pass
TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs. IOL 5000 cycles Temp Cycle	0/80 pass 0/80	0/80 pass 0/80 0/80	0/80 pass 0/80	0/80 pass 0/80
TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs. IOL 5000 cycles	0/80 pass 0/80 0/80	0/80 pass 0/80 0/80	0/80 pass 0/80 0/80	0/80 pass 0/80 0/80
TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs. IOL 5000 cycles Temp Cycle 1000 cycles Autoclave 96 hrs.	0/80 pass 0/80	0/80 pass 0/80 0/80	0/80 pass 0/80	0/80 pass 0/80
TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs. IOL 5000 cycles Temp Cycle 1000 cycles Autoclave	0/80 pass 0/80 0/80	0/80 pass 0/80 0/80	0/80 pass 0/80 0/80	0/80 pass 0/80 0/80
TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs. IOL 5000 cycles Temp Cycle 1000 cycles Autoclave 96 hrs. HTGB 1000 hrs.	0/80 pass 0/80 0/80 0/80	0/80 pass 0/80 0/80 0/80	0/80 pass 0/80 0/80 0/80	0/80 pass 0/80 0/80 0/80
TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs. IOL 5000 cycles Temp Cycle 1000 cycles Autoclave 96 hrs. HTGB 1000 hrs. MUR7030WT	0/80 pass 0/80 0/80 0/80 0/80	0/80 pass 0/80 0/80 0/80 0/80	0/80 pass 0/80 0/80 0/80 0/80	0/80 pass 0/80 0/80 0/80 0/80
TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs. IOL 5000 cycles Temp Cycle 1000 cycles Autoclave 96 hrs. HTGB 1000 hrs.	0/80 pass 0/80 0/80 0/80	0/80 pass 0/80 0/80 0/80	0/80 pass 0/80 0/80 0/80	0/80 pass 0/80 0/80 0/80
TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs. IOL 5000 cycles Temp Cycle 1000 cycles Autoclave 96 hrs. HTGB 1000 hrs. MUR7030WT TEST DESCRIPTION H3TRB 1000 hrs.	0/80 pass 0/80 0/80 0/80 0/80 Lot 1 0/80	0/80 pass 0/80 0/80 0/80 0/80 Lot 2 0/80	0/80 pass 0/80 0/80 0/80 0/80 0/80 Lot 3	0/80 pass 0/80 0/80 0/80 0/80 Control
TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs. IOL 5000 cycles Temp Cycle 1000 cycles Autoclave 96 hrs. HTGB 1000 hrs. MUR7030WT TEST DESCRIPTION H3TRB 1000 hrs. ESD	0/80 pass 0/80 0/80 0/80 0/80 0/80 Lot 1	0/80 pass 0/80 0/80 0/80 0/80 0/80	0/80 pass 0/80 0/80 0/80 0/80 0/80 Lot 3	0/80 pass 0/80 0/80 0/80 0/80 0/80 Control
TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs. IOL 5000 cycles Temp Cycle 1000 cycles Autoclave 96 hrs. HTGB 1000 hrs. MUR7030WT TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs.	0/80 pass 0/80 0/80 0/80 0/80 Lot 1 0/80	0/80 pass 0/80 0/80 0/80 0/80 Lot 2 0/80	0/80 pass 0/80 0/80 0/80 0/80 0/80 Lot 3	0/80 pass 0/80 0/80 0/80 0/80 Control
TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs. IOL 5000 cycles Temp Cycle 1000 cycles Autoclave 96 hrs. HTGB 1000 hrs. MUR7030WT TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs. IOL	0/80 pass 0/80 0/80 0/80 0/80 Lot 1 0/80 pass 0/80	0/80 pass 0/80 0/80 0/80 0/80 Lot 2 0/80 pass	0/80 pass 0/80 0/80 0/80 0/80 0/80 Lot 3 0/80 pass 0/80	0/80 pass 0/80 0/80 0/80 0/80 0/80 Control 0/80 pass
TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs. IOL 5000 cycles Temp Cycle 1000 cycles Autoclave 96 hrs. HTGB 1000 hrs. MUR7030WT TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs.	0/80 pass 0/80 0/80 0/80 0/80 Lot 1 0/80 pass	0/80 pass 0/80 0/80 0/80 0/80 0/80 Lot 2 0/80 pass 0/80	0/80 pass 0/80 0/80 0/80 0/80 0/80 Lot 3 0/80 pass	0/80 pass 0/80 0/80 0/80 0/80 0/80 Control 0/80 pass
TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs. IOL 5000 cycles Temp Cycle 1000 cycles Autoclave 96 hrs. HTGB 1000 hrs. MUR7030WT TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs. IOL 5000 cycles Temp Cycle 1000 cycles	0/80 pass 0/80 0/80 0/80 0/80 Lot 1 0/80 pass 0/80	0/80 pass 0/80 0/80 0/80 0/80 Lot 2 0/80 pass	0/80 pass 0/80 0/80 0/80 0/80 0/80 Lot 3 0/80 pass 0/80	0/80 pass 0/80 0/80 0/80 0/80 0/80 Control 0/80 pass
TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs. IOL 5000 cycles Temp Cycle 1000 cycles Autoclave 96 hrs. HTGB 1000 hrs. MUR7030WT TEST DESCRIPTION H3TRB 1000 hrs. ESD HTRB 1000 hrs. IOL 5000 cycles Temp Cycle	0/80 pass 0/80 0/80 0/80 0/80 Lot 1 0/80 pass 0/80	0/80 pass 0/80 0/80 0/80 0/80 0/80 Lot 2 0/80 pass 0/80	0/80 pass 0/80 0/80 0/80 0/80 0/80 Lot 3 0/80 pass 0/80	0/80 pass 0/80 0/80 0/80 0/80 0/80 Control 0/80 pass 0/80

Remaining Qualifications in process and expected completion dates: TO-247 Bipolar MJW21191 Dec. 19, 2000 TO-218 Bipolar MJH16006A Oct. 14, 2000

CHANGED PART IDENTIFICATION:

Devices from PSi can be identified with the assembly location CQ preceding the date code. Devices from Team Pacific will have the location code CX preceding the date code and ST Microelectronics devices have assembly code location DE.

The packages from PSi are all within the industry standard JEDEC outline.

In the case of the TO-247 the body of the package is identical, but the

lead length is .220" longer and the lead thickness is .003" thicker at

PSi than the current factory. The dimensions for the other two packages

are identical. The shipping tubes for the TO-247 are also slightly different dimensionally. They have a thinner but longer profile (.306"x1.81") than the current suppliers tubes (.470"x1.55). The tubes

for the other packages are similarly dimensioned.

ADDITIONAL INFORMATION:

For more information, you can contact the following -

TECHNOLOGY NAME EMAIL PHONE
Rectifier Kevin Kellar kevin.kellar@onsemi.com
Bipolar Jose Ramirez jose.l.ramirez@onsemi.com
MOSFET Catherine Chandioux c.chandioux@onsemi.com
33-5611-999-21

AFFECTED DEVICE LIST:

PART

BDV64B

BU323Z

BUS48AP

BUV48

BUV48A

MBR3045WT

MBR4015LWT

MBR4045WT

MBR6045WT

MBR7030WT

MJL21196

MJW16010

MJW16010A

MJW16012

MJW16018

MJW16206

MJW16212

MJW18020

MTW35N15E

MTW45N10E

MTW8N50E

MUR3020WT

MUR3060WT

TE02570

TIP145

TIP146

TIP147